Supporting Information

Enhanced Photoelectrochemical Water Splitting using Nanostructured Films: p-CuO Sensitized with Polyhedral n-Cu₂O Particles and CuS as Photocathode

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Figure S1. (a) SEM surface image and elemental EDX mappings of (b) Cu, (c) O and (d) S for the CuO/Cu₂O/CuS film.



Figure S2. (a) SEM cross-section image and (b)-(e) Elemental mapping by EDX of CuO/Cu₂O/CuS film.



Figure S3 – Linear voltammograms at 10 mV s⁻¹ under AM 1.5G pulsed illumination (100 mW cm⁻²) for the CuO/Cu₂O films obtained at different deposition charge densities of Cu₂O. Measurements carry out in 0.5 mol L⁻¹ Na₂SO₄ solution (pH 6).



Figure S4 – Linear voltammograms at 10 mV s⁻¹ under AM 1.5G pulsed illumination (100 mW cm⁻²) for CuO/Cu₂O/CuS films obtained with different numbers of SILAR cycles. Measurements carry out in 0.5 mol L⁻¹ Na₂SO₄ solution (pH 6).

Sample	$R_{\rm s}$ (Ω cm ²)	$R_{\rm ct}$ (Ω cm ²)	CPE		
			<i>СРЕ</i> (Т)	CPE (P)	Chi ²
CuO	2.30	248.15	1.49×10 ⁻⁴	0.69	9.22×10 ⁻⁵
CuO/Cu ₂ O	3.38	187.80	1.11×10-4	0.74	5.29×10 ⁻⁴
CuO/Cu ₂ O/CuS	2.95	132.47	1.79×10 ⁻⁴	0.74	1.28×10 ⁻⁴

Table S1. Parameters obtained from the adjustment of the EIS data for the CuO, CuO/Cu_2O and CuO, $CuO/Cu_2O/CuS$ films, using the equivalent circuit with one time constant in series (1TS) inserted in Figure 7.



Figure S5. SEM surface images and EDX elemental mapping for bare CuO (a) before and (b) after the stability test. SEM surface images and EDX elemental mapping for CuO/Cu₂O/CuS (c) before and (d) after the stability test.